## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10595221	TANAKA ET AL.
Examiner	Art Unit
DEREK S CHAPEL	2872

SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES				
Search Notes	Date	Examiner		
Consulted with Arnel Lavarias about the restriction requirement.	2/25/2008	DSC		

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	

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